

L Number	Hits	Search Text	DB	Time stamp
1	1358	(356/237.4,237.5,244).ccls.	USPAT	2004/07/07 12:18
2	46815	(wafer or semiconductor) near10 (test\$ or inspect\$ or station or convey\$ or monitor\$ or detect\$)	USPAT	2004/07/07 12:21
3	365	((356/237.4,237.5,244).ccls.) and ((wafer or semiconductor) near10 (test\$ or inspect\$ or station or convey\$ or monitor\$ or detect\$))	USPAT	2004/07/07 12:20
4	15032	(wafer or semiconductor) near15 rotat\$	USPAT	2004/07/07 12:21
5	93	((356/237.4,237.5,244).ccls.) and ((wafer or semiconductor) near10 (test\$ or inspect\$ or station or convey\$ or monitor\$ or detect\$)) and ((wafer or semiconductor) near15 rotat\$)	USPAT	2004/07/07 12:21